

Dual N-Channel MOSFET

General Description

The WSD4066DN33 is the highest performance trench Dual N-Channel MOSFET with extreme high cell density, which provide excellent $R_{DS(ON)}$ and gate charge for most of the synchronous buck converter applications.

The WSD4066DN33 meet the RoHS and Green Product requirement 100% E_{AS} guaranteed with full function reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% E_{AS} Guaranteed
- Green Device Available

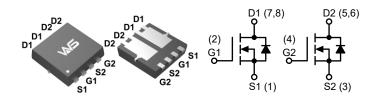
Product Summery

BV _{DSS}	R _{DS(ON)}	I _D	
40V	17mΩ	14A	

Applications

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

DFN3X3-8L Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter		Rating	Units	
V _{DS}	Drain-Source Voltage		40	V	
V _{GS}	Gate-Source Voltage	Gate-Source Voltage		V	
I _S	Diode Continuous Forward Current	T _A =25°C	2		
	Continuous Proin Compant	T _A =25°C	14	Δ	
I _D	Continuous Drain Current	T _A =70°C	9.8	А	
I _{DM} ¹	Pulse Drain Current Tested	T _A =25°C	28		
P _D	Maximum Power Dissipation	T _A =25°C	2.5	W	
		T _A =70°C	1.68	VV	
R _{θJL}	Thermal Resistance-Junction to Lead	Steady State	10	°C/W	
R _{eJA}	The second Designation to Austrian to	t≤10s	42.5	8000	
	Thermal Resistance-Junction to Ambient	Steady State ²	75	°C/W	
I _{AS} ³	Avalanche Current, Single pulse	L=0.5mH	10	А	
E _{AS} ³	Avalanche Energy, Single pulse	L=0.5mH	25	mJ	
T _{STG}	Storage Temperature Range Maximum Junction Temperature		-55 to 150	°C	
TJ			150		



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Electrical Characteristics (T_J =25°C, Unless Otherwise Noted)

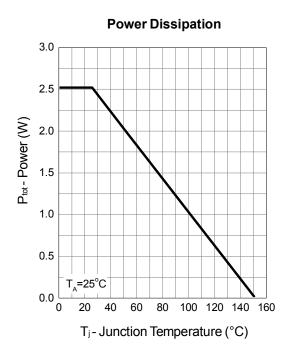
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Units		
Static Chara	Static Characteristics							
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250μA	40			V		
7	V _{DS} =32V , V _{GS} =0V			1.0				
I _{DSS}	Zero Gate Voltage Drain Current	T _J =85°C			30	μA		
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _{DS} =250μA	1.0	1.5	2.0	V		
I _{GSS}	Gate Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA		
D 4	D : 0 0 11 D : 1	V _{GS} =10V , I _D =14A		14	17	mΩ		
R _{DS(ON)} ⁴	Drain-Source On-state Resistance	V _{GS} =4.5V , I _D =12A		17	20			
Diode Chara	Diode Characteristics							
V _{SD} ⁴	Diode Forward Voltage	I _{SD} =1A, V _{GS} =0V		0.75	1.1	V		
t _{rr}	Reverse Recovery Time	L CA -II /-II 400A/		13		ns		
Q _{rr}	Reverse Recovery Charge	I _{DS} =6A , dl _{SD} /dt=100A/μs		8.7		nC		
Dynamic Ch	aracteristics ⁵				•			
R _g	Gate Resistance	V _{DS} =0V , V _{GS} =0V , F = 1.0MHz		2.5		Ω		
C _{iss}	Input Capacitance			815		pF		
C _{oss}	Output Capacitance	V _{GS} =0V , V _{DS} =20V , Frequency = 1.0MHz		95				
C _{rss}	Reverse Transfer Capacitance			60				
$T_{d(on)}$	Turn-on Delay Time			7.8				
T _r	Turn-on Rise Time	V_{DD} =20V, R_L =20 Ω , I_{DS} =1A,		6.9		ns		
$T_{d(off)}$	Turn-off Delay Time	V_{GEN} =10V , R_{G} =6 Ω		22.4				
T _f	Turn-off Fall Time			4.8				
Gate Charge	Gate Charge Characteristics ⁵							
Q_g	Total Gate Charge	V _{DS} =20V , V _{GS} =10V , I _{DS} =6A		15.7	22			
Qg	Total Gate Charge			7.5	10.5			
Q _{gth}	Threshold Gate Charge	\/ -20\/ \/ -45\/ \ -64		1.85		nC		
Q _{gs}	Gate-Source Charge	V _{DS} =20V , V _{GS} =4.5V , I _{DS} =6A		3.24				
Q _{gd}	Gate-Drain Charge			2.75				

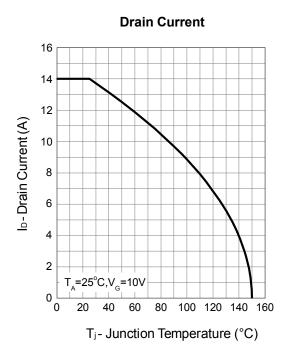
Note:

- 1. Pulse width limited by max. junction temperature.
- 2. Surface Mounted on 1in² pad area, t=999sec.
- 3. UIS tested and pulse width limited by maximum junction temperature 150 $^{\circ}$ C (initial temperature T_J =25 $^{\circ}$ C).
- 4. Pulse test ; pulse width≤300µs, duty cycle≤2%.
- 5. Guaranteed by design, not subject to production testing.

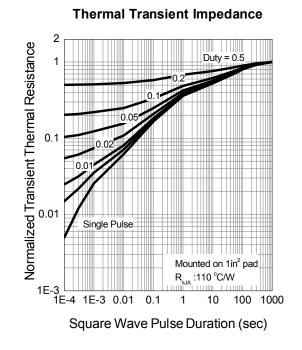


Typical Characteristics





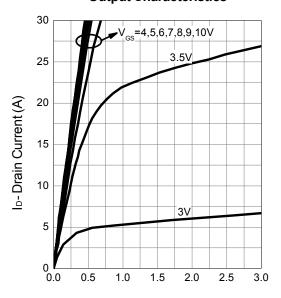
Safe Operation Area 100 (V) 10 20 11 11 100 11 100 11 100 1





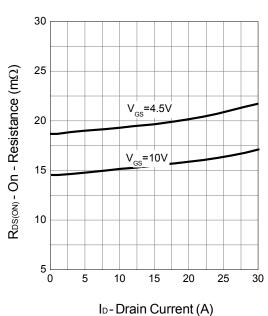
Typical Characteristics (Cont.)

Output Characteristics

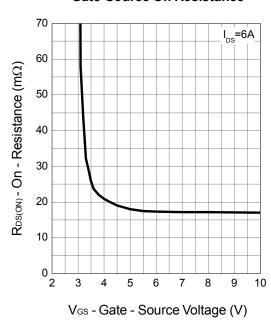


V_{DS} - Drain - Source Voltage (V)

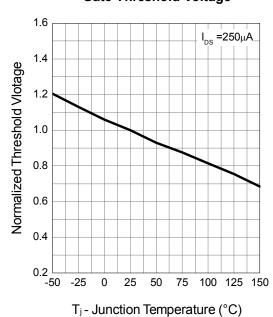
Drain-Source On Resistance



Gate-Source On Resistance

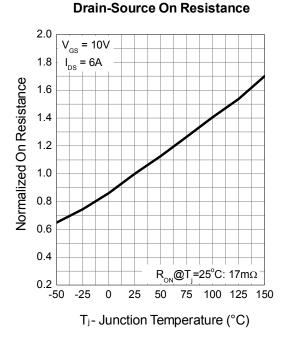


Gate Threshold Voltage

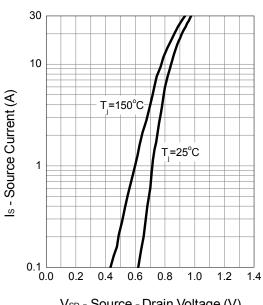




Typical Characteristics (Cont.)

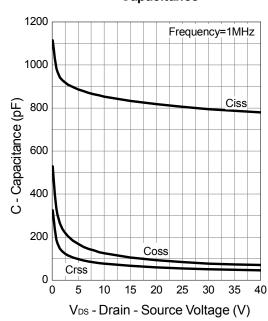


Source-Drain Diode Forward

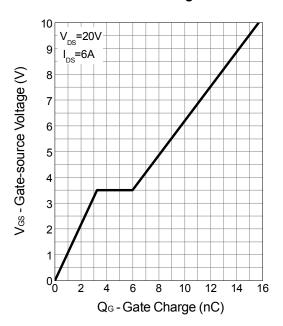


V_{SD} - Source - Drain Voltage (V)

Capacitance



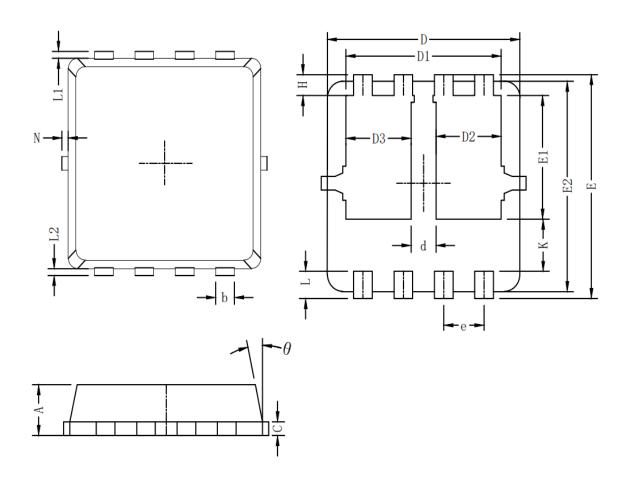
Gate Charge







Packaging information



Symbol	Dim in mm			
	min	typ	max	
А	0.6	0.75	0.9	
b	0.2	0.3	0.4	
С	0.15	0.2	0.25	
D	3	3.1	3.2	
D1	2.3	2.45	2.6	
D2/D3	0.8	1	1.2	
E	3.15	3.3	3.45	
E1	1.43	1.73	1.93	
E2	2.9	3.05	3.2	
е	0.65BSC			
Н	0.2	0.35	0.5	
K	0.57	0.77	0.87	
L	0.3	0.4	0.5	
L1/L2	0.1REF			
θ	8°	10°	13°	
N	0		0.15	
d	0.3	0.4	0.5	



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